

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Marco Wedowski et al. Art Unit : 2837
Serial No. : 10/598,481 Examiner : Unknown
Filed : August 31, 2006 Conf. No. : 5997
Title : METHODS FOR MANUFACTURING REFLECTIVE OPTICAL ELEMENTS,
REFLECTIVE OPTICAL ELEMENTS, EUV-LITHOGRAPHY APPARATUSES
AND METHODS FOR OPERATING OPTICAL ELEMENTS AND EUV-
LITHOGRAPHY APPARATUSES, METHODS FOR DETERMINING THE
PHASE SHIFT, METHODS FOR...

MAIL STOP AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

Applicants also enclose a copy of the International Search Report for the corresponding PCT Application No. PCT/EP2005/050985.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: June 29, 2007

/Sean P. Daley/

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 17979-046US1	Application No. 10/598,481
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Marco Wedowski et al.	
		Filing Date August 31, 2006	Group Art Unit

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,307,395	4/26/1994	Seely et al.			
	AB	6,781,685	8/24/2004	Hamm			
	AC	2005/0104015	5/19/2005	Wedowski et al.			
	AD	2005/0087699	4/28/2005	Miyake			
	AE	2007/0114466	5/24/2007	Wedowski et al.			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AF	1 243 970	9/25/2002	EP				
	AG	1 351 258	10/8/2003	EP				X
	AH	1 351 258	10/8/2003	EP			Abstract only	
	AI	2002-243669	8/28/2002	JP				X
	AJ	2002-243669	8/28/2002	JP			Abstract only	
	AK	WO 04/10755	1/29/2004	WIPO				

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AL	Y. Muramatsu et al., "Total-electron-yield X-ray standing-wave measurements of multilayer X-ray mirrors for the interface structure evaluation," Microprocesses and Nanotechnology Conference, October 2001 International, 2001.

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	